

Challenges of reliability assessment and enhancement in autonomous systems

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Composing graph theory and deep neural networks to evaluate SEU type soft error effects

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Enabling cross-layer reliability and functional safety assessment through ML-based compact models

Alexandrescu, Dan; **Balakrishnan, Aneesh**; Lange, Thomas; Glorieux, Maximilien Proceedings : 2020 26th IEEE International Symposium on On-Line Testing and Robust System Design : IOLTS 2020, Napoli, Italy, July 13-16, 2020 : virtual edition 2020 / 6 p. : ill <https://doi.org/10.1109/IOLTS50870.2020.9159750>

Gate-level graph representation learning : a step towards the improved stuck-at faults analysis

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Machine learning clustering techniques for selective mitigation of critical design features

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Machine learning to tackle the challenges of transient and soft errors in complex circuits

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Modeling gate-level abstraction hierarchy using graph convolutional neural networks to predict functional de-rating factors

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Modeling soft-error reliability under variability

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On antagonism between side-channel security and soft-error reliability in BNN inference engines

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On the estimation of complex circuits functional failure rate by machine learning techniques

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RESCUE EDA Toolset for interdependent aspects of reliability, security and quality in nanoelectronic systems design

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The validation of graph model-based, gate level low-dimensional feature data for machine learning applications

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Understanding multidimensional verification : where functional meets non-functional

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